

<b>Notice of References Cited</b>	Application/Control No. 09/423,401	Applicant(s)/Patent Under Reexamination LI ET AL.	
	Examiner Jerome Jackson Jr.	Art Unit 2815	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Cohen et al. APPLIED PHYSICS LETTERS Vol. 73 No. 6 10 August 1998 "Native defect engineering...GaAs". pp803-805.
	V	
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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